IC kp=1000 dt_simulation=3.125e-05 k_attrito=0.15 metodo=RK4
Average tracking error 0.071076320 m
Average inf norm error 0.064921585 m

OSC kp=1000 dt_simulation=3.125e-05 k_attrito=0.15 metodo=RK4
Average tracking error 0.092953345 m
Average inf norm error 0.076295332 m

IC kp=1000 dt_simulation=6.25e-05 k_attrito=0.15 metodo=RK4
Average tracking error 0.071076233 m
Average inf norm error 0.064921483 m

OSC kp=1000 dt_simulation=6.25e-05 k_attrito=0.15 metodo=RK4
Average tracking error 0.060648145 m
Average inf norm error 0.052992189 m

IC kp=1000 dt_simulation=0.000125 k_attrito=0.15 metodo=RK4
Average tracking error 0.071076063 m
Average inf norm error 0.064921256 m

OSC kp=1000 dt_simulation=0.000125 k_attrito=0.15 metodo=RK4
Average tracking error 0.053082881 m
Average inf norm error 0.044945533 m

IC kp=1000 dt_simulation=0.00025 k_attrito=0.15 metodo=RK4
Average tracking error 0.071075301 m
Average inf norm error 0.064920464 m

OSC kp=1000 dt_simulation=0.00025 k_attrito=0.15 metodo=RK4
Average tracking error 0.043781974 m
Average inf norm error 0.037628834 m

IC kp=1000 dt_simulation=0.0005 k_attrito=0.15 metodo=RK4
Average tracking error 0.071073762 m
Average inf norm error 0.064918801 m

OSC kp=1000 dt_simulation=0.0005 k_attrito=0.15 metodo=RK4
Average tracking error 0.100050941 m
Average inf norm error 0.088724371 m

IC kp=1000 dt_simulation=0.001 k_attrito=0.15 metodo=RK4
Average tracking error 0.071070488 m
Average inf norm error 0.064915644 m

OSC kp=1000 dt_simulation=0.001 k_attrito=0.15 metodo=RK4
Average tracking error 0.090653338 m
Average inf norm error 0.081766053 m